Semiconductor devices — Time Dependent Dielectric Breakdown (TDDB) test for gate dielectric films

ICS 31.080.01



National foreword

This British Standard is the UK implementation of EN 62374:2007. It is identical to IEC 62374:2007.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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Semiconductor devices Time Dependent Dielectric Breakdown (TDDB) test for gate dielectric films

(IEC 62374:2007)

Dispositifs à semiconductors -Essai de rupture diélectrique en fonction du temps (TDDB) pour films diélectriques de grille (CEI 62374:2007) Halbleiterbauelemente -Prüfung des zeitabhängigen dielektrischen Durchbruchs (TDDB) für dielektrische Gate-Schichten (IEC 62374:2007)

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